TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

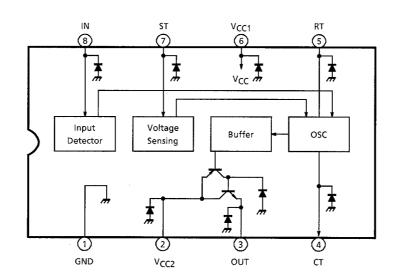
TA8026AP

FLASHER CONTROLLER

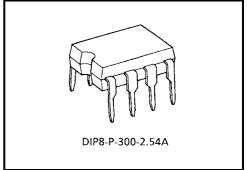
The TA8026AP is designed as an automotive flasher controller. It can issue a rapied-flashing warning when a lamp failure occurs. It operates accurately in wide ranges of supply voltages and operating temperatures. It incorporates an accurate reference voltage circuit which compensates for lamp current characteristic variations due to supply voltage changes.

FEATURES

- Large output current : I_{OUT} = 300mA (Max.)
- Low standby current $: I_{CC} = 1.0 \text{mA} (Typ.)$
- Reference voltage characterized by small temperature drift.
- Built-in circuit that compensates for variations in lamp voltage characteristics.
- Output from combination of PNP and NPN transistors with suppression diode.
- Wide operating temperature : Ta = -40 to 110°C
- DIP -8 pin.



BLOCK DIAGRAM AND PIN LAYOUT

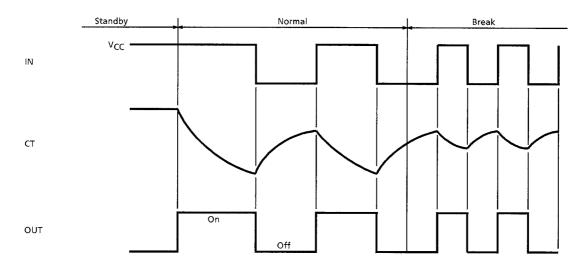


Weight: 0.45 g (typ.)

PIN DESCRIPTION

PIN No.	SYMBOL	DESCRIPTION
1	GND	Grounded
2	V _{CC2}	Power supply pin (2)
3	OUT	Open-emitter output of complementary combination of PNP and NPN transistors.
4	СТ	A capacitor is connected between V_{CC} and CT. This layout determines the flashing interval of the flasher.
5	RT	A resistor is connected between RT and CT. This layout determines the flashing interval of the flasher.
6	V _{CC1}	Power supply pin (1)
7	ST	Current detection pin. The lamp current is detected through a shunt resistor connected between V_{CC1} and ST.
8	IN	Detection pin for lamp operation.

TIMING CHART



MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Supply Voltage	V _{CC}	28	V	
Power Dissipation	PD	300 *	mW	
Output Current	IOUT	300	mA	
Input Voltage	V _{IN}	-0.3~V _{CC}	V	
Operating Temperature	T _{opr}	-40~110	°C	
Storage Temperature	T _{stg}	-55~150	°C	
Lead Temperature-Time	T _{sol}	260 (10s)	°C	

*: Ta ≤110°C

ELECTRICAL CHARACTERISTICS (V_{CC} = 12V, Ta = -40~110°C)

CHARACTERISTIC	SYMBOL	PIN	TEST CONDITION	MIN	TYP.	MAX	UNIT
Operating Voltage	V _{opr}	V _{CC}		6	—	18	V
Current Consumption		GND	Standby, Ta = 25°C	0.6	0.9	1.4	mV
Current Consumption	ICC		Output on, Ta = 25°C	2.5	4.0	6.0	
Output Voltage	V _{OH}	OUT	R _L = 82Ω	_	_	1.3	V
Leakage Current	I _{LEAK}	OUT	V _{OUT} = 0V	-100	—	_	μA
		СТ	$V_{IN} = V_{CC} \sim V_{CC} - 5V$	-10	—	10	μΑ
Input Current	I _{IN}	ST	V _{IN} = V _{CC}	-10	—	10	
Input Current		IN	V _{IN} = 12V	_	_	20	
			V _{IN} = 0V	-1.5	-2.5	-3.5	mA
Input Voltage	V _{IL}	IN		_	_	0.4	×V _{CC}
input voltage	VIH	IIN		0.6	_	_	
	V _{TH}	- ST	V _{CC} = 8V	16	21	26	mV
			V _{CC} = 11V	25	31	37	
Detection Voltage			V _{CC} = 14V	30	36	42	
Delection voltage	ΔV_{TH} / T			-60	_	60	μV/ °C
	ΔV _{TH} / ΔV _{CC}			2.7	3.3	3.9	mV/ V
		ST	V _{CC} = 8V	3	7	11	mV
Condition Detect Voltage *1	V _{THO}		V _{CC} = 11V	5	10	15	
			V _{CC} = 16V	8	13	18	
Flashing Interval		OUT		690	706	723	ms
Flashing Interval (At fail detection)		OUT	Ст = 3.3uF. Rт = ADJ *2	315	324	333	
On Duty		OUT	$-C_{T} = 3.3 \mu F, R_{T} = ADJ$ *2	45	50	55	%
On Duty (At fail detection)		OUT		30	_	50	

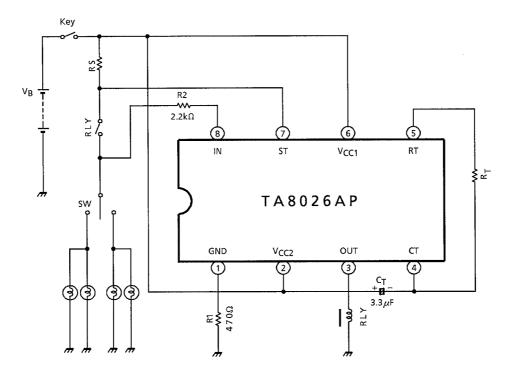
* 1: The minimum detection voltage to be able to operate.

* 2 : Adjust the flashing interval to 706ms by changing RT while keeping $C_T = 3.3 \mu F$ at room temperature.

FLASHING FREQUENCY CHARACTERISTICS DETECTION VOLTAGE CHARACTERISTICS 200 80 $V_{CC} = 11V$ 160 60 50 (%) () () 40 C/M 40 120 ΡΠΤΥ DUTY VTH 30 20 80 20 10 40L ___0 80 20 40 60 8 10 16 18 12 14 DETECTION VOLTAGE (mV) $V_{CC} \langle V \rangle$

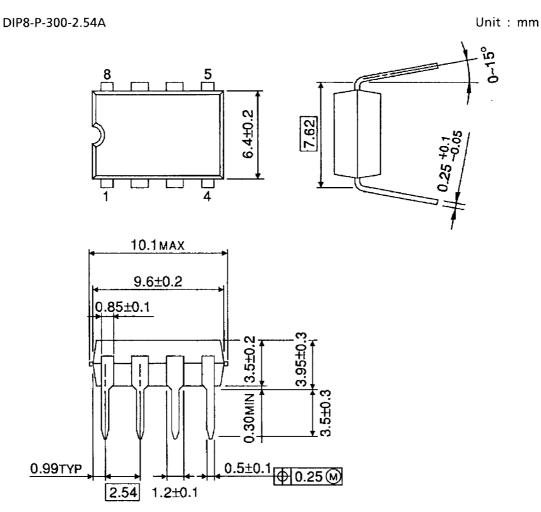
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EXAMPLE OF APPLICATION CIRCUIT



Note: The tolerance of R1 and R2 is within ±5%.

PACKAGE DIMENSIONS



Weight: 0.45g (Typ.)

RESTRICTIONS ON PRODUCT USE

Handbook" etc..

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